

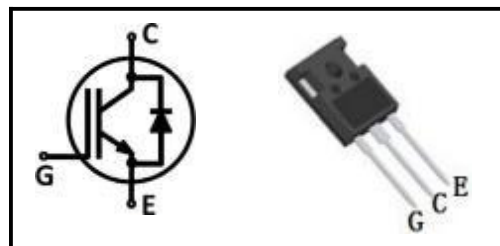
特征/Features

- 饱和压降为正温度系数，易于并联使用
Easy parallel switching capability due to positive temperature coefficient in V_{CEsat}
- 低饱和压降，快速开关
Low V_{CEsat} , fast switching
- 高可靠性及热稳定性，良好的参数一致性
High reliability and thermal stability, good parameter consistency

型号/Type	打标/Marking	封装/Package
QMW30N120E	QM30N120E	TO-247

应用领域/Applications

- 焊接/Welding



最大额定值/Maximum Rated Values

Item	Symbol	Value	Unit
集电极-发射极电压 Collector-emitter voltage	V_{CE}	1200	V
集电极电流 DC collector current, limited by T_{vjmax} $T_C=25^\circ C$ $T_C=130^\circ C$	I_C	60 30	A
集电极脉冲电流 Pulsed collector current, t_p limited by T_{jmax1}	I_{Cpuls}	120	
二极管正向电流 Diode forward current, limited by T_{jmax} $T_C=25^\circ C$ $T_C=100^\circ C$	I_F	30 15	
二极管脉冲电流 Diode pulsed current, t_p limited by T_{jmax1}	I_{Fpuls}	60	V
栅极-发射极电压 Gate-emitter voltage	V_{GE}	± 20	
瞬态栅极-发射极电压 Transient Gate-emitter voltage ($t_p \leq 10\mu s, D < 0.01$)		± 30	
耗散功率 Power dissipation $T_C=25^\circ C$ $T_C=130^\circ C$	P_{tot}	333	W
		166	
工作结温 Operating junction temperature	T_j	-40~175	°C
储存温度 Storage temperature	T_{stg}	-55~150	
焊接温度 Soldering temperature, wave soldering 1.6mm (0.063in.) from case for 10s		260	
安装扭矩, M3 螺钉最大安装过程: 3 Mounting torque, M3 screw Maximum of mounting processes: 3	M	0.6	Nm

1) Defined by design. Not subject to production test.

电学特性/Electrical Characteristics

静态特性/Static Characteristics (at $T_j=25^\circ\text{C}$ unless otherwise specified)

Item	Symbol	Conditions	Min.	Typ.	Max.	Unit
集电极-发射极击穿电压 Collector-emitter breakdown voltage	$V_{(BR)CES}$	$V_{GE}=0V$, $I_C=0.25mA$	1200	-	-	V
集电极-发射极饱和电压 Collector-emitter saturation voltage	$V_{CE(sat)}$	$V_{GE}=15V$, $I_C=30A$ $T_j=25^\circ\text{C}$	-	1.60	2.10	
		$T_j=150^\circ\text{C}$	-	2.55	-	
		$T_j=175^\circ\text{C}$	-	2.40	-	
阈值电压 G-E threshold voltage	$V_{GE(th)}$	$I_C=1.2mA$, $V_{CE}=V_{GE}$	5.0	5.8	6.5	
集电极-发射极漏电流 C-E leakage current	I_{CES}	$V_{CE}=1200V$, $V_{GE}=0V$ $T_j=25^\circ\text{C}$	-	-	0.01	mA
		$T_j=175^\circ\text{C}$	-	-	4.0	
栅极-发射极漏电流 G-E leakage current	I_{GES}	$V_{CE}=0V$, $V_{GE}=20V$	-	-	100	nA

动态特性/Dynamic Characteristics

Item	Symbol	Conditions	Min.	Typ.	Max.	Unit
输入电容 Input capacitance	C_{iss}	$V_{CE}=25V$, $V_{GE}=0V$, $f=1MHz$	-	7100	-	pF
输出电容 Output capacitance	C_{oss}		-	100	-	
反馈电容 Reverse transfer capacitance	C_{rss}		-	66	-	
栅电荷 Gate charge	Q_G	$V_{CC}=400V$, $I_C=30A$, $V_{GE}=15V$	-	365	-	nC

热学特性/Thermal Characteristics

Item	Symbol	Conditions	Min.	Typ.	Max.	Unit
结-外壳热阻 IGBT thermal resistance, junction-case	R_{thJC}	-	-	-	0.45	K/W
二极管结-外壳热阻 Diode thermal resistance, junction-case	R_{thJCD}	-	-	-	1.2	
结-环境热阻 Thermal Resistance, junction-ambient	R_{thJA}	-	-	-	40	

IGBT开关特性(感性负载) / IGBT Switching Characteristics

Item	Symbol	Conditions	Min.	Typ.	Max.	Unit	
开通延迟时间 Turn-on delay time	$t_{d(on)}$	$T_J=25^{\circ}C,$ $V_{CC}=600V,$ $I_C=30A,$ $V_{GE}=0/15V,$ $R_G=10\Omega,$ <i>Inductive load</i>	-	91	-	ns	
上升时间 Rise time	t_r		-	68	-		
关断延迟时间 Turn-off delay time	$t_{d(off)}$		-	471	-		
下降时间 Fall time	t_f			-	77	-	
开通损耗 Turn-on energy	E_{on}			-	1.91	-	mJ
关断损耗 Turn-off energy	E_{off}			-	1.30	-	
开关损耗 Total switching energy	E_{ts}			-	3.21	-	
开通延迟时间 Turn-on delay time	$t_{d(on)}$		$T_J=175^{\circ}C,$ $V_{CC}=600V,$ $I_C=30A,$ $V_{GE}=0/15V,$ $R_G=10\Omega,$ <i>Inductive load</i>	-	87	-	ns
上升时间 Rise time	t_r			-	71	-	
关断延迟时间 Turn-off delay time	$t_{d(off)}$	-		543	-		
下降时间 Fall time	t_f			-	126	-	
开通损耗 Turn-on energy	E_{on}			-	2.30	-	mJ
关断损耗 Turn-off energy	E_{off}			-	1.72	-	
开关损耗 Total switching energy	E_{ts}			-	4.02	-	

二极管开关特性/Diode Characteristics

Item	Symbol	Conditions	Min.	Typ.	Max.	Unit
二极管正向压降 Diode forward voltage	V_F	$V_{GE}=0V, I_F=15A$ $T_J=25^{\circ}C$	-	2.35	-	V
		$T_J=150^{\circ}C$	-	2.05	-	
		$T_J=175^{\circ}C$	-	2.0	-	
反向恢复时间 Diode reverse recovery time	t_{rr}	$T_J=25^{\circ}C,$ $V_R=400V,$ $I_F=15A,$ $di_F/dt=600A/\mu s$	-	184	-	ns
反向恢复电荷 Diode reverse recovery charge	Q_{rr}		-	0.94	-	μC
反向恢复峰值电流 Diode peak reverse recovery current	I_{rrm}		-	10.4	-	A
反向恢复时间 Diode reverse recovery time	t_{rr}	$T_J=150^{\circ}C,$ $V_R=400V,$ $I_F=15A,$ $di_F/dt=600A/\mu s$	-	303	-	ns
反向恢复电荷 Diode reverse recovery charge	Q_{rr}		-	3.41	-	μC
反向恢复峰值电流 Diode peak reverse recovery current	I_{rrm}		-	20.8	-	A

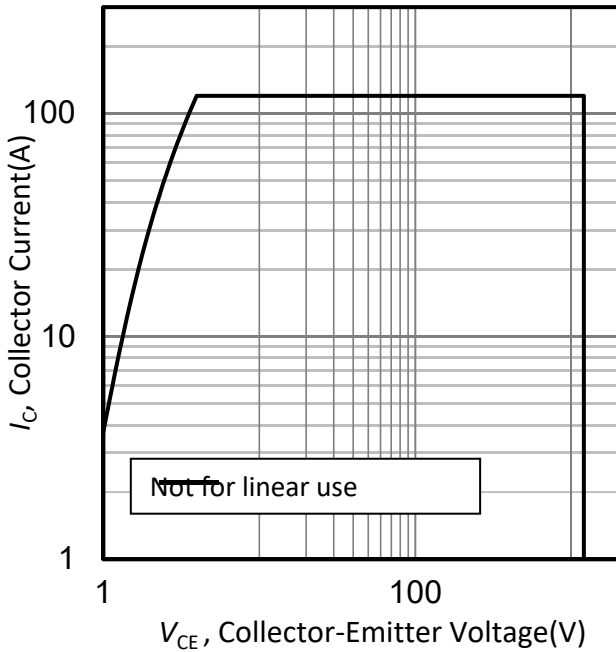


Figure 1..正向偏置安全工作区/Forward bias safe operating area
($D=0, T_C=25^\circ\text{C}, T_{vj}\leq 175^\circ\text{C}, V_{GE}=15\text{V}$)

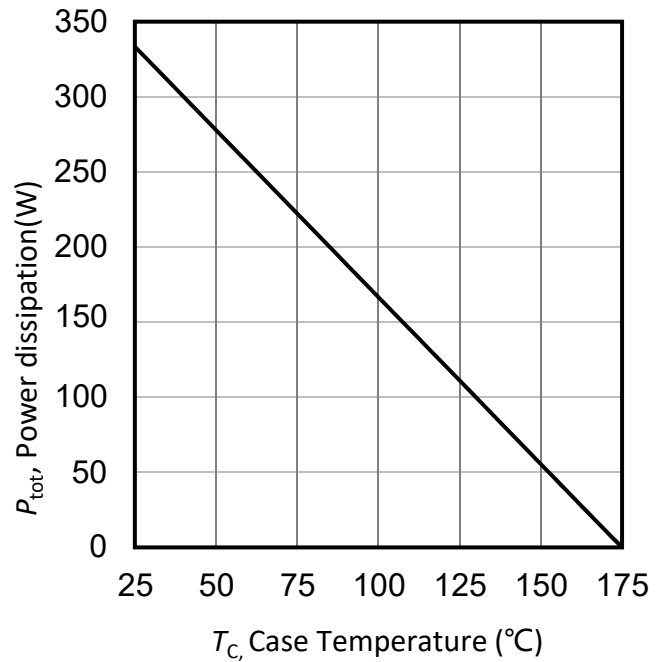


Figure 2. 功耗与外壳温度的关系/Power dissipation as a function of case temperature
($T_{vj}\leq 175^\circ\text{C}$)

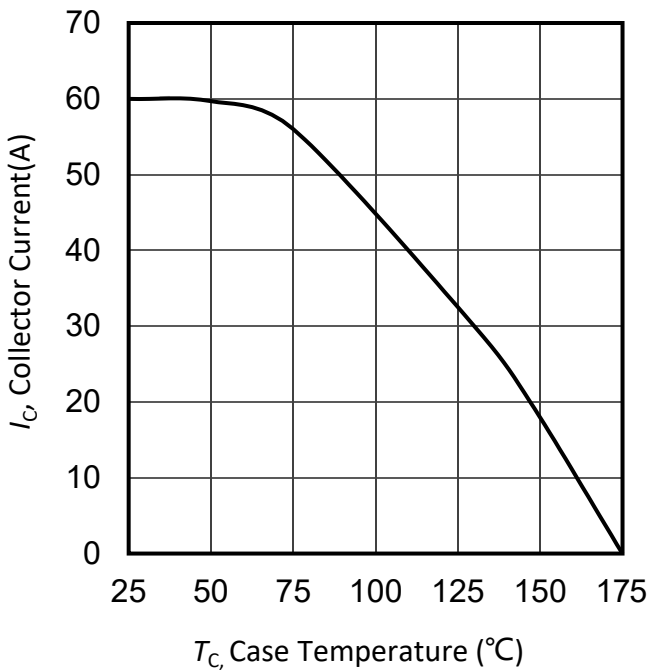


Figure 3. 集电极电流与外壳温度的关系 /Collector current as a function of case temperature
($T_{vj}\leq 175^\circ\text{C}, V_{GE}\geq 15\text{V}$)

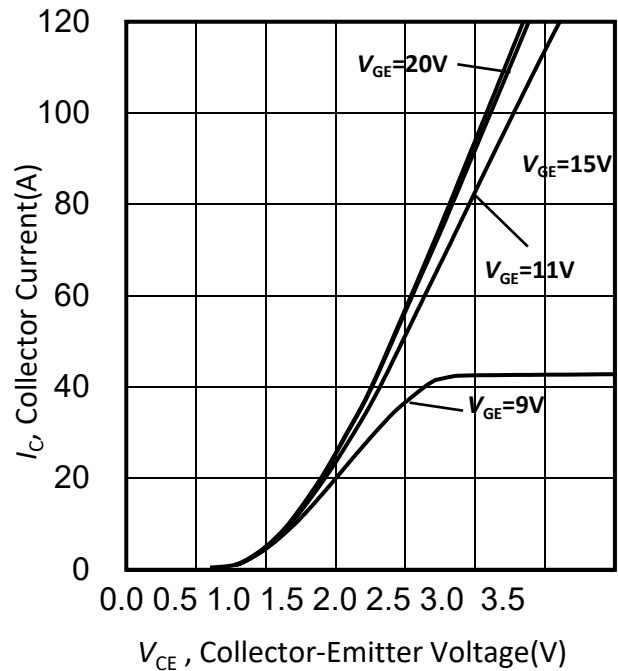


Figure 4. 典型输出特性/Typical output characteristic
($T_{vj}=25^\circ\text{C}$)

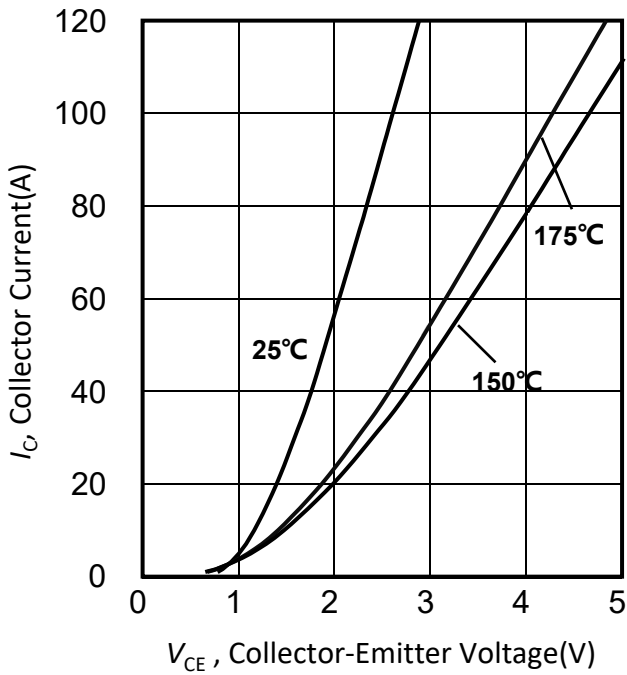


Figure 5. 集电极-发射极饱和电压特性
/Collector-emitter saturation voltage characteristic
($V_{GE}=15V$)

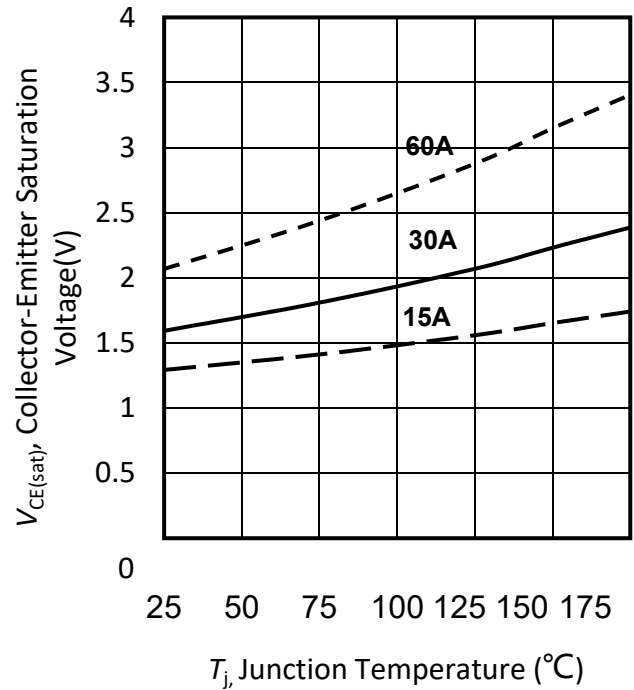


Figure 6. 典型集电极-发射极饱和电压与结温的关系
/Typical collector-emitter saturation voltage as a function of junction temperature
($V_{GE}=15V$)

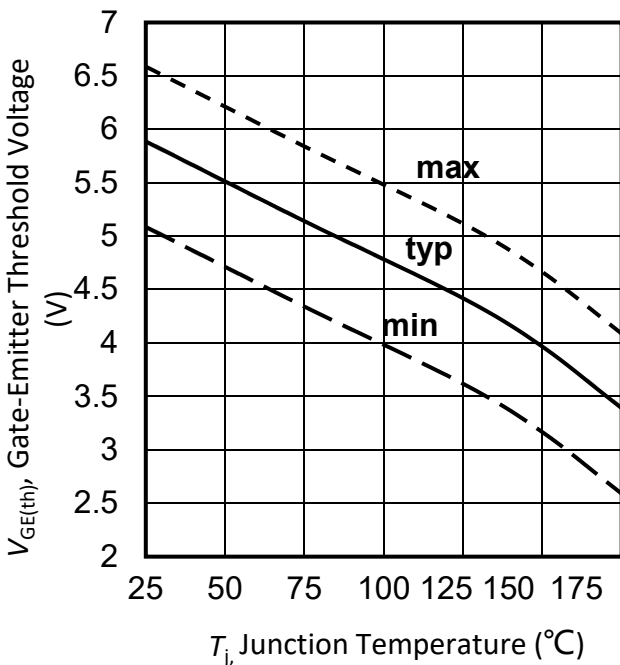


Figure 7. 栅极-发射极阈值电压与结温的关系
/Gate-emitter threshold voltage as a function of junction temperature
($I_C=1.2mA$)

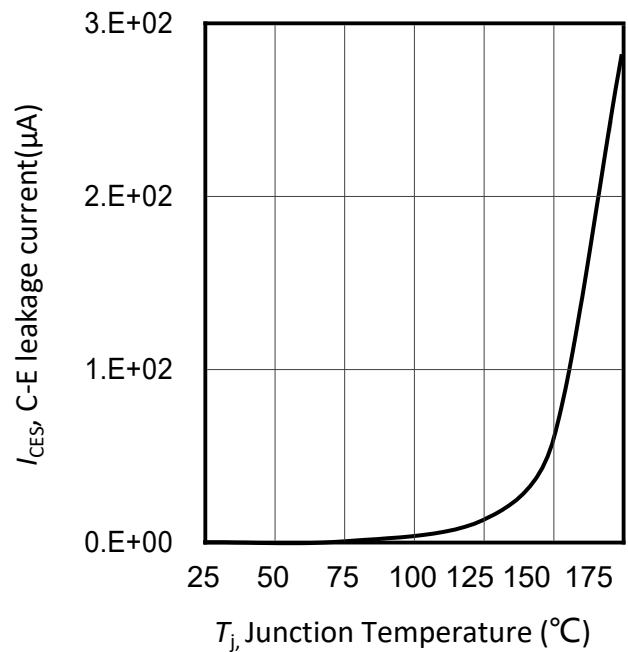


Figure 8. 典型 C-E 漏电流与结温的关系
/Typical C-E leakage current as a function of junction temperature
($V_{CE}=1200V, V_{GE}=0V$)

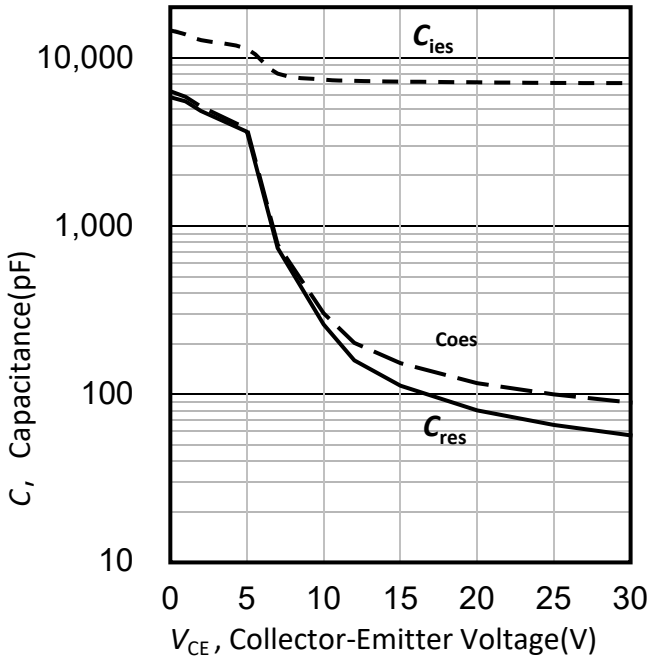


Figure 9. 典型电容与集电极-发射极电压的关系/Typical capacitance as a function of collector-emitter voltage ($V_{GE}=0V$, $f=1MHz$)

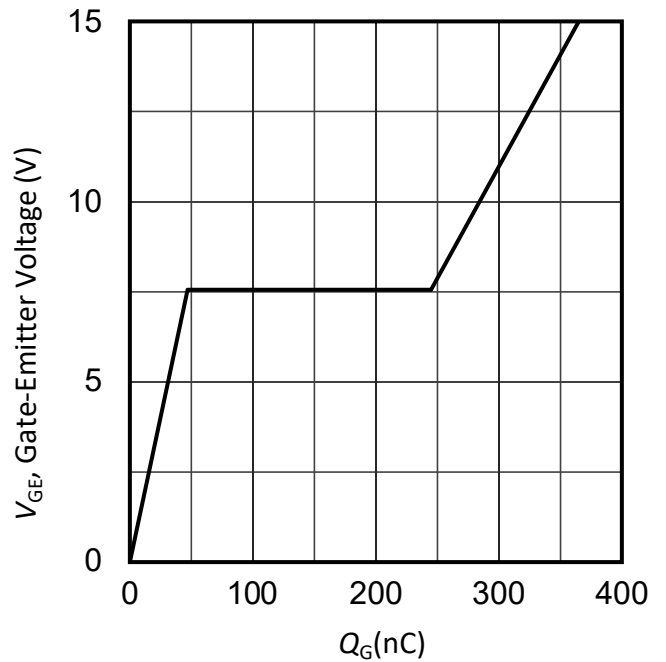


Figure 10. 典型栅极电荷/Typical gate charge
($V_{CC}=400V$, $I_C=30A$)

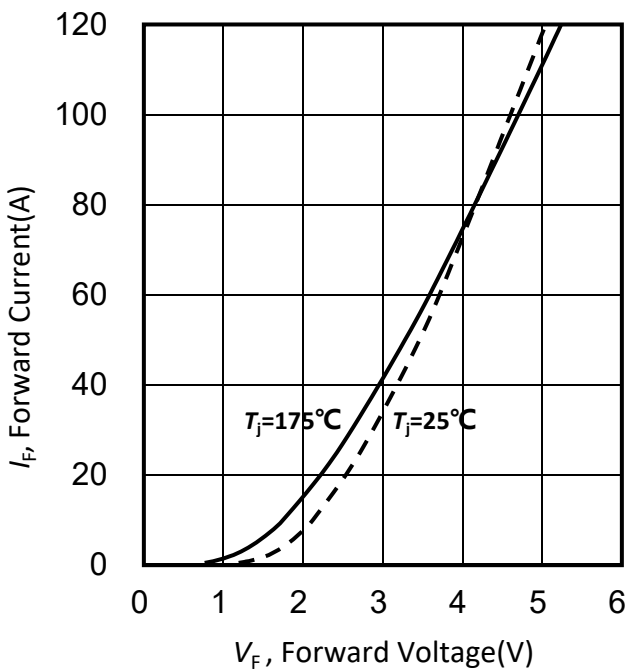


Figure 11. 典型二极管正向电流与正向电压的函数关系/Typical diode forward current as a function of forward voltage

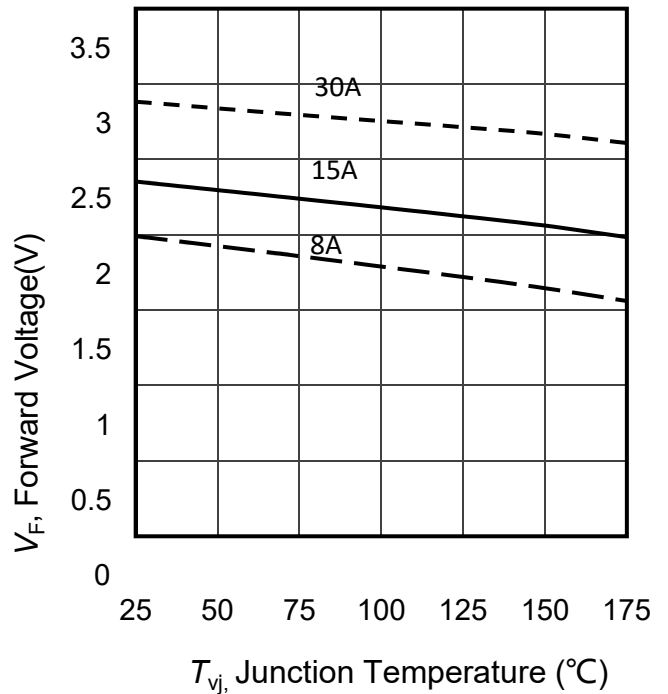


Figure 12. 典型二极管正向电压与结温的关系/Typical diode forward voltage as a function of junction temperature

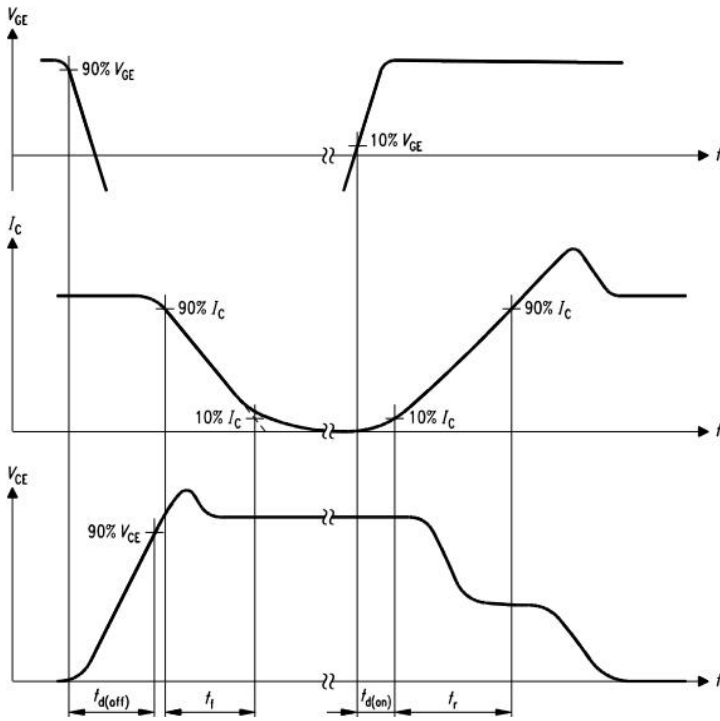


Figure A. 开关时间的定义/Definition of switching times

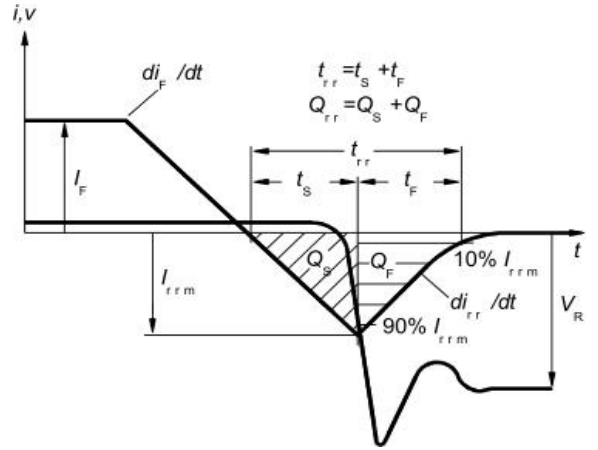


Figure C. 二极管开关特性的定义/Definition of diodes switching characteristics

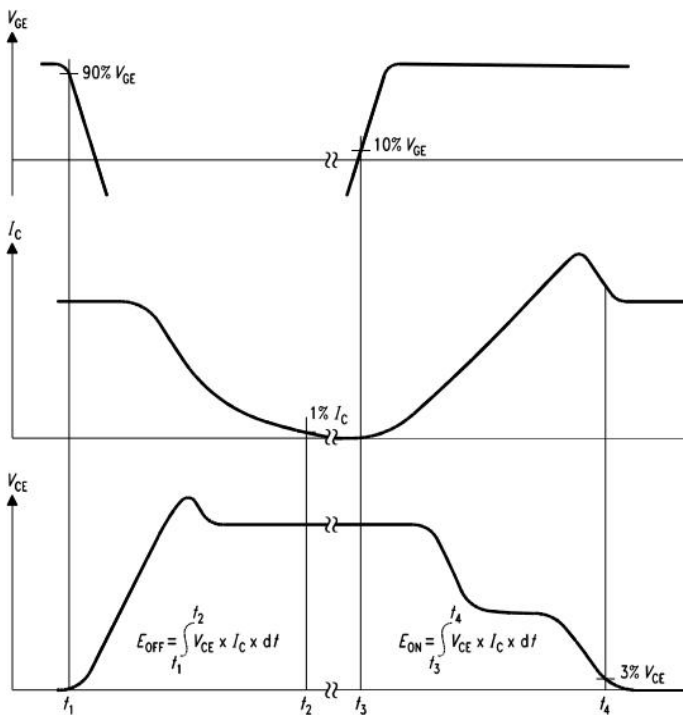


Figure B. 开关损耗的定义/Definition of switching losses

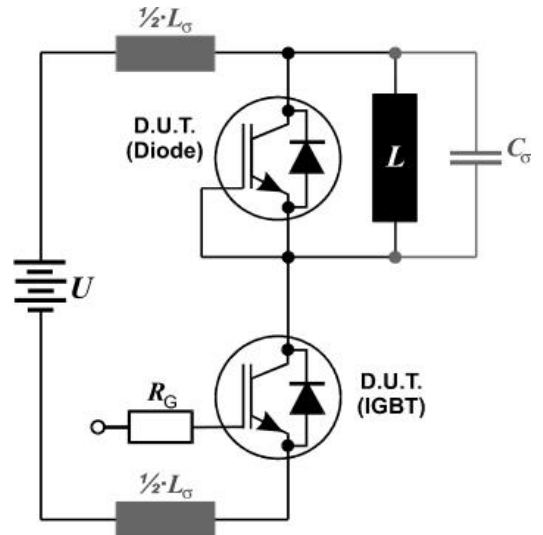
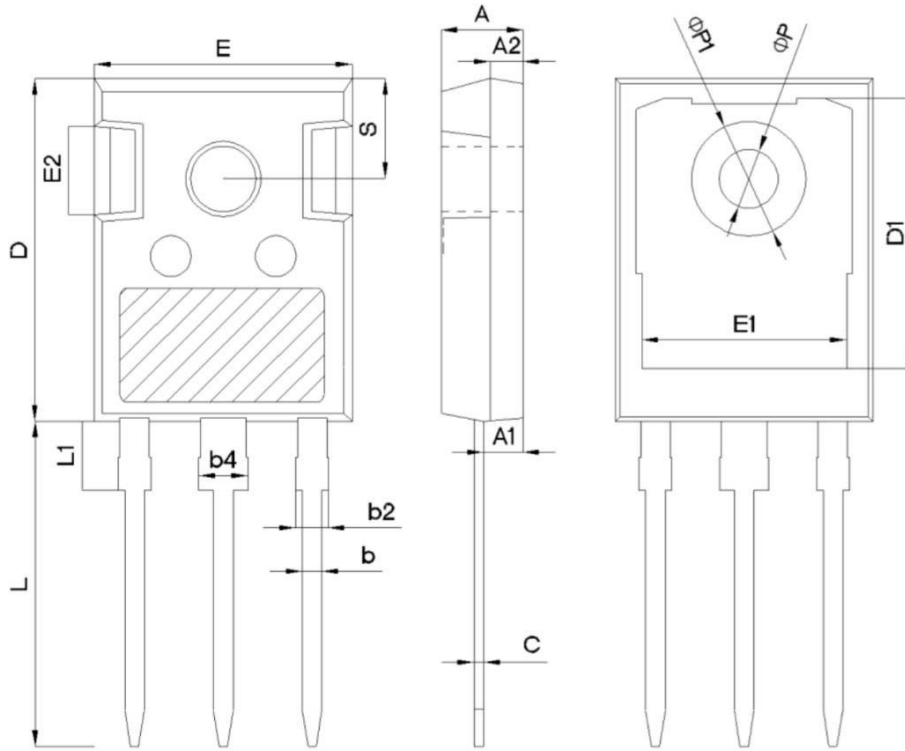


Figure D. 开关测试电路/Switching test circuit

TO-247



SYMBOL	mm		
	MIN	NOM	MAX
A	4.80	5.00	5.20
A1	2.21	2.41	2.61
A2	1.85	2.00	2.15
b	1.11	1.21	1.36
b2	1.91	2.01	2.21
b4	2.91	3.01	3.21
c	0.51	0.61	0.75
D	20.70	21.00	21.30
D1	16.25	16.55	16.85
E	15.50	15.80	16.10
E1	13.00	13.30	13.60
E2	4.80	5.00	5.20
E3	2.30	2.50	2.70
e	5.44BSC		
L	19.62	19.92	20.22
L1	-	-	4.30
ΦP	3.40	3.60	3.80
ΦP1	-	-	7.30
S	6.15BSC		

修订历史/Revision History:

修订 /Revision	主题（自上次修订以来的主要变化） /Subjects (major changes since last revision)	日期 /Date
1.0	Initial Version	2022-09
2.0	Update the English and Chinese versions	2023-04

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